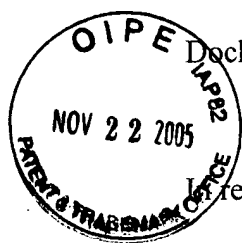


*JBW*



Docket No.: 49959-377

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Is the Application of

Dieter WINKLER, et al.

Application No.: 10/823,968

Filed: April 13, 2004

For: CHARGED PARTICLE BEAM MICROSCOPE WITH MINICOLUMN

: Customer Number: 20277  
:  
: Confirmation Number: 5313  
:  
: Group Art Unit: 2881  
:  
: Examiner: Kalimah Fernandez  
:

**RESPONSE**

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

The following remarks are submitted in response to the Office Action dated August 23, 2005.

Claims 1, 7, and 8 are pending in the application.

In the Office Action, claim 1 was indicated as being allowed.

Claim 7 was rejected under 35 U.S.C. §103(a) as being unpatentable over U.S. Patent 5,270,990 (Mizasawa). Claim 8 was rejection under 35 U.S.C. §103(a) as being unpatentable over Mizasawa in view of U.S. Patent 4,760,567 (Crewe). These rejections are respectfully traversed. Applicants hereby request reconsideration and allowance of the claims in view of the following arguments.

Regarding the obviousness rejection of independent claim 7 based on Mizasawa, this reference fails to teach or suggest the claimed microscope wherein imaging of every point on a wafer by a plurality of minicolumns is enabled by a turntable rotating the wafer. Mizasawa relates to an apparatus that uses a plurality of modulatable electron beams for tracking error